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In June 1998, the **Journal** and The Electrochemical Society reached a point of no return. For the first time since July 1977, the **Journal** offered no rapid-publication section. We have been brought to this departure of the Letters Section after years of planning and there will be no turning back, just a single backward glance. This month, July 1998, the Letters Section becomes its own publication — *Electrochemical and Solid-State Letters*. *Letters* is the first, and only, electrochemical journal dedicated exclusively to rapid publication with a lagtime goal of eight to ten weeks to electronic publication. *Letters* is a joint publication of ECS and the Electron Devices Society (EDS) of the Institute of Electrical and Electronics Engineers (IEEE), bolstering its solid-state component. The departure of the Letters Section will bring a new emphasis to its content, facilitating growth in quality and quantity. *Letters* will be a part of the member benefits package of both ECS and EDS, giving it an initial circulation of more than 15,000 individuals and institutions, twice that of the **Journal**.

The Letters Section of the **Journal** grew out of the Accelerated Brief Communications (ABCs). In July 1977, Editor Norman Hackerman created ABCs as a short lagtime section of the **Journal**. They were printed from camera-ready copies from the authors and inserted into each issue at the end of the Technical Papers Section. In May 1991, Editor Barry Miller moved ABCs to the front of the **Journal**, had them typeset, and renamed them the Letters Section. These short papers have provided authors an opportunity to disseminate important new information in a timely manner.

After 21 years of nurturing a rapid-publication section, the **Journal** now improves upon the concept and moves forward, allowing the need for rapid publication to be better met by a new publication. Perhaps better said by Weber: "*Past all thought of 'if' or 'when' — no use resisting — abandon thought and let the dream descend...*" "*Past the point of no return, the final threshold — what... secrets will we learn beyond the point of no return?*"



Paul Kohl
Editor

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